

**Search Notes****Application/Control No.**

10/552,694

**Examiner**

SYED ZAIDI

**Applicant(s)/Patent under Reexamination**

FRICKE ET AL.

**Art Unit**

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	452.2	4/11/2008	SZ
455	453	4/11/2008	SZ
455	512	4/11/2008	SZ
455	412.1	4/11/2008	SZ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	4/11/2008	SZ
Inventor : FRICKE ET AL.	4/11/2008	SZ
IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	4/11/2008	SZ
(455/452.2 455/453 455/512).CCLS.	4/11/2008	SZ
Consulted with SPE Nick Corsaro	4/11/2008	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner